

Robert Hull

List of Publications by Year in descending order

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#	ARTICLE	IF	CITATIONS
1	In Situ Transmission Electron Microscopy of High-Temperature Inconel-625 Corrosion by Molten Chloride Salts. <i>Journal of the Electrochemical Society</i> , 2021, 168, 051507.	2.9	6
2	The effect of cooling conditions on Ti 6%Al 4%V microstructure observed using high-temperature in-situ scanning electron microscopy. <i>Journal of Materials Research</i> , 2021, 36, 717-728.	2.6	1
3	Influence of Controlled Cooling Rates During Thermal Processing of Ti 6% Al 4% V Alloys Using In-Situ Scanning Electron Microscopy. <i>MRS Advances</i> , 2020, 5, 1603-1611.	0.9	2
4	Electrochemical memristive devices based on submonolayer metal deposition. <i>APL Materials</i> , 2019, 7, 101121.	5.1	8
5	Accelerated Electromigration Study of Cobalt Thin Films by In-Situ TEM. <i>Microscopy and Microanalysis</i> , 2019, 25, 1902-1903.	0.4	1
6	Stochasticity in materials structure, properties, and processing—A review. <i>Applied Physics Reviews</i> , 2018, 5, .	11.3	15
7	In Situ Correlative Microscopy Combining Transmission Electron Microscopy and Secondary Ion Mass Spectrometry. <i>Microscopy and Microanalysis</i> , 2018, 24, 380-381.	0.4	1
8	Directed Self-Assembly of Ge Quantum Dots Using Focused Si ²⁺ Ion Beam Patterning. <i>Scientific Reports</i> , 2018, 8, 9361.	3.3	4
9	In situ EC-TEM Studies of Metal Thin Film Corrosion in Liquid Solutions at Elevated Temperatures. <i>Microscopy and Microanalysis</i> , 2018, 24, 254-255.	0.4	7
10	Investigation of Structural Evolution of Li _{1.1} V ₃ O ₈ by In Situ X-ray Diffraction and Density Functional Theory Calculations. <i>Chemistry of Materials</i> , 2017, 29, 2364-2373.	6.7	40
11	Distributions of kinetic pathways in strain relaxation of heteroepitaxial films. <i>Journal of Materials Research</i> , 2017, 32, 3977-3991.	2.6	0
12	New Methods for Measuring Chemistry and Temperature Using Scanning Ion and Electron Beams. <i>Microscopy and Microanalysis</i> , 2016, 22, 610-611.	0.4	0
13	An In Situ Transmission Electron Microscopy Study of Localized Corrosion on Aluminum. <i>MRS Advances</i> , 2016, 1, 1877-1882.	0.9	2
14	Substrates with Programmable Heater Arrays for In-Situ Observation of Microstructural Evolution of Polycrystalline Films: Towards Real Time Control of Grain Growth. <i>MRS Advances</i> , 2016, 1, 1947-1952.	0.9	2
15	Liquid Cell TEM of Al Thin Film Corrosion under Potentiostatic Polarization. <i>Microscopy and Microanalysis</i> , 2015, 21, 973-974.	0.4	4
16	Controlled Nucleation of Ge Islands on Si and Self-Assembly of Nanoscale Island Clusters. <i>International Journal of High Speed Electronics and Systems</i> , 2014, 23, 1420003.	0.7	0
17	Metastable Structures in Al Thin Films Before the Onset of Corrosion Pitting as Observed using Liquid Cell Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2014, 20, 462-468.	0.4	30
18	Ion-induced Auger Electron Spectroscopy as a Potential Route to Chemical Focused-Ion Beam Tomography. <i>Microscopy and Microanalysis</i> , 2014, 20, 310-311.	0.4	2

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19	Corrosion of Metal Films Observed Using In Situ and Ex Situ Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2014, 20, 1540-1541.	0.4	1
20	Studies of Corrosion of Al Thin Films using Liquid Cell Transmission Electron Microscopy. <i>Materials Research Society Symposia Proceedings</i> , 2013, 1525, 1.	0.1	4
21	Nano-scale Chemistry of Complex Self-Assembled Nanostructures in Epitaxial SiGe Films. <i>Materials Research Society Symposia Proceedings</i> , 2013, 1551, 75-80.	0.1	1
22	A Low Electron Voltage Approach to Increase Spatial Resolution of Temperature Mapping in Thermal Scanning Electron Microscopy. <i>Materials Research Society Symposia Proceedings</i> , 2013, 1525, 1.	0.1	0
23	The material dependence of temperature measurement resolution in thermal scanning electron microscopy. <i>Applied Physics Letters</i> , 2013, 102, 113107.	3.3	5
24	Enhanced magnetic and electrical properties in amorphous Ge:Mn thin films by non-magnetic codoping. <i>Journal of Applied Physics</i> , 2012, 111, 033916.	2.5	6
25	Correlation of Nanoscale Structure and Magnetic Properties in Manganese Doped Germanium Dilute Magnetic Semiconductors. <i>Materials Research Society Symposia Proceedings</i> , 2011, 1305, 1.	0.1	0
26	Modulation of the magnetism in ion implanted $\text{Mn}_x\text{Ge}_{1-x}$ thin films by rapid thermal anneal. <i>Journal of Applied Physics</i> , 2010, 108, .	2.5	8
27	Analysis of the three-dimensional ordering of epitaxial Ge quantum dots using focused ion beam tomography. <i>Applied Physics Letters</i> , 2006, 88, 263103.	3.3	9
28	Composition and stress fields in undulated $\text{Si}_{0.7}\text{Ge}_{0.3}\text{Si}(100)$ thin films. <i>Journal of Applied Physics</i> , 2006, 100, 083510.	2.5	8
29	Guided Control of Cu_2O Nanodot Self-Assembly on $\text{SrTiO}_3(100)$. <i>Materials Research Society Symposia Proceedings</i> , 2004, 811, 146.	0.1	0
30	Nano-scale Stress and Compositional Analysis of Epitaxial $\text{Si}_{1-x}\text{Ge}_x/\text{Si}(100)$ Undulated Films. <i>Materials Research Society Symposia Proceedings</i> , 2004, 854, U3.8.1.	0.1	0
31	Heteroepitaxial Self-Assembly of Higher-Complexity Structures By Combining Growth Control with Nanopatterning. <i>Materials Research Society Symposia Proceedings</i> , 2004, 849, 81.	0.1	0
32	NANO-ELECTRONICS: SOME CURRENT ASPECTS AND PROSPECTS. , 2003, , .		0
33	Nanoscale Tomographic Imaging using Focused Ion Beam Sputtering, Secondary Electron Imaging and Secondary Ion Mass Spectrometry. <i>Microscopy and Microanalysis</i> , 2001, 7, 934-935.	0.4	3
34	SiGe Epilayer Stress Relaxation: Quantitative Relationships Between Evolution of Surface Morphology and Misfit Dislocation Arrays. <i>Materials Research Society Symposia Proceedings</i> , 2001, 696, 1.	0.1	1
35	Development of a Nanoindenter for In Situ Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2001, 7, 507-517.	0.4	97
36	Growth and characterizations of InP self-assembled quantum dots embedded in InAlP grown on GaAs substrates. <i>Journal of Electronic Materials</i> , 2001, 30, 471-476.	2.2	8

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37	Strain Accommodation and Relief in GeSi/Si Heteroepitaxy. Series on Directions in Condensed Matter Physics, 1999, , 299-367.	0.1	8
38	Self-Assembled Iii-Phospide Quantum Dots Grown by Metalorganic Chemical Vapor Deposition. Materials Research Society Symposia Proceedings, 1999, 583, 39.	0.1	2
39	Strain compensated In _{1-x} GaxAs(x<0.47) quantum well photodiodes for extended wavelength operation. Applied Physics Letters, 1998, 73, 2263-2265.	3.3	23
40	In Situ Studies of the Interaction of Dislocations with Point Defects during Annealing of Ion Implanted Si/SiGe/Si (001) Heterostructures. Microscopy and Microanalysis, 1998, 4, 294-307.	0.4	39